


Contacts:**Aehr Test Systems**

Greg Perkins

V.P. Worldwide Sales & Service

(510) 623-9400 x241

Financial Relations Board

Tricia Ross

Analyst/Investor Contact

(213) 486-6544

**AEHR TEST SYSTEMS ANNOUNCES FOLLOW-ON WAFERPAK™
CONTACTOR AND FOX™-1 SYSTEM UPGRADE ORDERS**

Fremont, CA (September 11, 2008) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, announced today that it has received over \$7 million in follow-on orders for WaferPak contactors and FOX-1 system upgrades from a leading manufacturer of semiconductor memory devices. The WaferPak contactors and system upgrades are scheduled to ship during the next six months.

“We are very excited to have received these follow-on orders,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “This further validates the production worthiness of our full wafer contact solution. The FOX-1 system, using a WaferPak contactor, allows parallel testing of thousands of die on a 300mm wafer with only a single touchdown. This technology has proven to be extremely cost-effective for our customer.”

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is most effective for test and short burn-in applications. Other members of Aehr Test’s FOX family of products such as the FOX-15 and FOX-V are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS, FOX, MTX and MAX systems and the DiePak® carrier. The ABTS is Aehr Test’s newest system for packaged part Test During Burn-in for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC

manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX and WaferPak contactor technologies, acceptance by customers of the FOX systems and WaferPak contactors shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K report and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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